Search Notes

Application/Control No.		Applicant(s)/Patent under Reexamination	
09/963,871	LEE ET AL.	LEE ET AL.	
Examiner	Art Unit		
Eric Kuiper	2154		

SEARCHED					
Class	Subclass	Date	Examiner		
· ·	_				
-					
		_			

	INTERFERENCE SEARCHED					
Subclass	Date	Examiner				
	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Performed Inventor search on PALM	11/29/2005	EIK		
Conducted PLUS search	11/21/2005	EJK		
Searched EAST databases See attached Search History	12/1/2005	ETV		
Searched IEEE Xplore Database	12/1/2005	EJK		
Searched INSPEC Database	12/1/2005	EJK		